

SEARCHED			
Class	Sub.	Date	Exmr.
702	64	3/18/04	me
	65		
	110		
	118		
	119		
	120		
	121		
	122-125		
	183		
714	724	3/19/04	
	725		
	726		
	727		
324	73.1		
	763-765		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	Date	Exmr.
East-Test Search (Semiconductor or semiconductor) "Integrated Circuits" or "IC") and "Shift register" and ((selector or selecting or selected or select) with buffer) and "flip-flop" and (test or testing or tested or tests)	3/19/04	me
East: (tristate near (buffer or buffers) with (impedance or impedances or resistor or resistors) and (flip-flop" or flip-flops")	3/19/04	me
IEEE Search by In Vendor's name	3/19/04	me

INTERFERENCE SEARCHED			
Class	Sub.	Date	Exmr.

**Best Available Copy**

(RIGHT OUTSIDE)